



11-29-02

2829
#6A
12/4/02
amrDocket No.: W1878.0169/P169
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Tomoaki Aihara

Application No.: 09/832,666

Group Art Unit: 2829

Filed: April 11, 2001

Examiner: J. Nguyen

For: METHOD AND APPARATUS FOR
INSPECTING SEMICONDUCTOR
DEVICERECEIVED
DEC - 3 2002
TECHNOLOGY CENTER 2800AMENDMENT/SUBMISSIONBox Non-Fee Amendment
Assistant Commissioner for Patents
Washington, DC 20231

Dear Sir:

This is a response to the Office Action mailed August 28, 2002 in the above-identified application. Reconsideration of the application is respectfully requested.

FEE CALCULATION

Any additional fee required has been calculated as follows:

___ If checked, "Small Entity" status is claimed.

	Claims Remaining After Amendment	Highest Number Previously Paid	Number Extra Claims Present	Rate	Additional Fee
Total	29	- 29* =		x	0.00
Independent	4	- 4** =		x	0.00
First presentation of Multiple Dependent Claim(s) (if applicable)					
TOTAL					0.00

*not less than 20

** not less than 3